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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/809,327	JIN ET AL.	
Examiner	Art Unit	
Mike Oi	2871	

SEARCHED						
Class	Subclass	Date	Examiner			
349	114;138; 113;110 106;44 139;96;	3/28/2006	ZQQ			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
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East search US-PGPUB;USPAT;USOCR; EPO;JPO;DERWENT;IBM_TDB; (see search history printout)	3/28/2006	ZQQ				
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